Freeform Search

Database:
```
US Pre-Grant Publication Full-Text Database
US Patents Full-Text Database
US OCR Full-Text Database
EPO Abstracts Database
JPO Abstracts Database
Derwent World Patents Index
IBM Technical Disclosure Bulletins
```

Term:
```
((measur$3 or determin$3) near3 thickness) same
(layer or film) same mask$3 same pattern$3 same
(cmp or polish$4) same (etch$3 or remov$3 or
```

Display: `10` Documents in **Display Format:** `CIT` **Starting with Number** `1`

Generate: ○ **Hit List** ⦿ **Hit Count** ○ **Side by Side** ○ **Image**

[Search] [Clear] [Interrupt]

Search History

DATE: Wednesday, January 26, 2005   Printable Copy   Create Case

Set Name side by side	Query	Hit Count	Set Name result set
	DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=ADJ		
L3	((measur$3 or determin$3) near3 thickness) same (layer or film) same mask$3 same pattern$3 same (cmp or polish$4) same (etch$3 or remov$3 or reduc$3)	45	L3
L2	thickness same (layer or film) same mask$3 same pattern$3 same (cmp or polish$4) same (etch$3 or remov$3 or reduc$3)	1659	L2
L1	thickness same (layer or film) same mask$3 same pattern$3 same (cmp or polish$4)	1885	L1

END OF SEARCH HISTORY